

TEST REPORT

Applicant/Manufacturer: AGM MOBILE LIMITED
Address: FLAT/RM 2253 22/F HOI TAI FACTORY ESTATE TSING YEUNG
CIRCUIT TUEN MUN NT HONG KONG CHINA
Report Number: 2501X79555E-RF-07A

Test Standard (s)

Item 19 of Article 2 Paragraph 1

Sample Description

Product Type: TWS Bluetooth Headset
Model No.: AGM OPEN BUDS 1
Multiple Model(s) No.: N/A
Trade Mark: N/A
Date Received: 2025-09-26
Issue Date: 2025-12-23

Test Result:	Pass▲
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▲ In the configuration tested, the EUT complied with the standards above.

Prepared and Checked By:

Ruby Huang

Ruby Huang
RF Engineer

Approved By:

Nancy Wang

Nancy Wang
RF Supervisor

Note: The information marked * is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included.
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Bay Area Compliance Laboratories Corp. (Shenzhen)

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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
0	2501X79555E-RF-07A	Original Report	2025-12-23

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Technical Parameters	Radio Type	Bluetooth
	Modulation Type	GFSK, $\pi/4$ -DQPSK, 8DPSK
	Frequency Range	2402-2480MHz
	Rated Output Power	Left:0.02 mW/MHz
	Antenna Gain[#]	1.7 dBi (It is provided by the applicant)
Nominal Power Supply		DC 3.7V from battery or DC 5V from Charging case
Sample serial number		3AOC-3 (Assigned by BACL, Shenzhen)
Sample/EUT Status		Good condition
Adapter Information		N/A
Note:The testing data for left ear.		

Objective

The objective of the manufacturer is to demonstrate compliance with Certification Ordinance Article 2-1-19, rules and limits for this device including:

- Frequency Error
- Occupied Bandwidth and Spreading Bandwidth
- Transmitter Spurious Emission and Unwanted Emission Intensity
- Antenna Output Power And Output Power Tolerance
- Receiver Spurious Emission Strength
- Frequency Hopping Dwell Time
- Interference Prevention Function
- Construction Protection Confirmation

Test Method

MIC Notice No.88 Appendix No.43

Measurement Uncertainty

Item	Expanded Measurement uncertainty
Frequency Error	56.6Hz(k=2, 95% level of confidence)
Occupied Channel Bandwidth	109.2kHz(k=2, 95% level of confidence)
RF output power, conducted	0.86dB(k=2, 95% level of confidence)
Unwanted Emission, conducted	1.60dB(k=2, 95% level of confidence)
Duty Cycle	±1%
Temperature	±1°C
Supply voltages	±0.4%
Humidity	±1%

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 5F(B-West) , 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China.

Each test item follows test standards and with no deviation.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a testing mode which was selected by manufacturer.

Normal/Extreme Voltage Condition [#]		
NV	Normal Voltage	3.7
LV	Low Voltage	3.5
HV	High Voltage	4.2
Note: extreme voltage test conditions were declared by manufacturer.		
The EUT works with a battery, power deviation of the RF circuit is less than 1% when extreme voltage supplied, therefore the test only performed at normal condition. Details as following:		
Voltage Condition	Input (V _{DC})	RF System Voltage (V _{DC})
NV	3.7	3.3
LV	3.5	3.3
HV	4.2	3.3

EUT Exercise Software

Exercise Software [#]	FCC_assist_1.0.2.2
Power Level [#]	7

Equipment Modifications

No modification was made to the EUT tested.

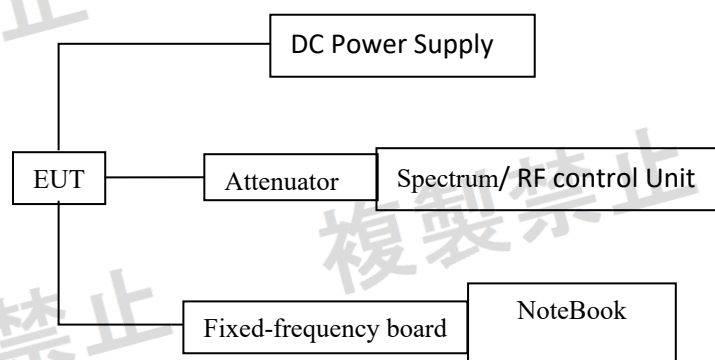
Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
DELL	Notebook	Latitude E6410	11429208685
instek	DC Power Supply	GPS-3030DD	EM832096
TELESKY	Fixed-frequency board	CP2102 MODULES	/

External I/O Cable

Cable Description	Length(m)	From/Port	To
Unshielded detachable DC cable*2	0.6	DC Power Supply	EUT
Unshielded detachable DC cable	0.1	Fixed-frequency board	EUT

Configuration of Test Setup



SUMMARY OF TEST RESULTS

MIC Notice No.88 Appendix No.43 Article 2, Paragraph 1, Item 19	Description of Test	Result
1	Frequency Error	Compliant
2	Occupied Bandwidth and Spreading Bandwidth	Compliant
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliant
4	Antenna Output Power and Output Power Tolerance	Compliant
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliant
6	Transmission Antenna Gain	Not Applicable
7	Transmission Radiation Angle Width	Not Applicable
8	Frequency Hopping Dwell Time	Compliant
9	Interference Prevention Function	Compliant
10	Construction Protection Confirmation	Compliant

Not Applicable - This test item was not required for the output power less than 6.91 dBm/MHz (E.I.R.P)

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
Tonscend	RF control Unit	JS0806-2	19D8060154	2025/07/18	2026/07/17	BACL Cal	c)
instek	DC Power Supply	GPS-3030DD	EM832096	NCR	NCR	/	/
Fluke	Digital Multimeter	287	19000011	2025/04/29	2026/04/28	BACL Cal	c)
Unknown	6dB Attenuator	Unknown	F-03-EM123	2025/06/26	2026/06/25	BACL Cal	d)
Rohde & Schwarz	Spectrum Analyze	FSU26	200982	2025/08/12	2026/08/11	BACL Cal	c)
Rohde & Schwarz	Spectrum Analyzer	FSV40-N	102259	2025/09/01	2026/08/31	CCIC	c)
Rohde& Schwarz	Wideband Radio Communication Tester	CMW500	141718	2025/07/18	2026/07/17	BACL Cal	c)

Note: Calibration Method

a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) or a designated calibration agency under Article 102-18 paragraph (1)

b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) ~Japan Calibration Service System~

c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1)

d) Calibration conducted by using other equipment that listed above from a) to c)

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

REQUIREMENTS AND TEST PROCEDURES

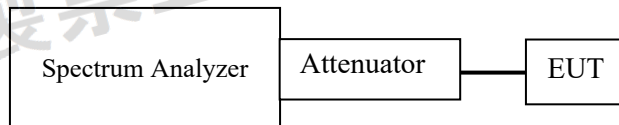
Frequency Error

Limit

50 ppm or below

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous carrier wave without modulation” by stopping frequency-hopping mode.

Spectrum Analyzer Conditions

- Center Frequency: Frequency to measure (2402 MHz, 2441MHz, and 2480MHz)
- RBW: 1kHz, VBW:3kHz
- Span: 300kHz
- Sweep time: Auto
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Single Sweep
- Marker: Spot

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.

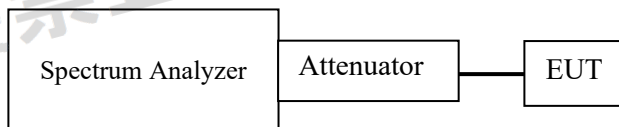
Occupied Bandwidth and Spreading Bandwidth

Limit

- Occupied bandwidth: FH $\leq$ 83.5 MHz; OFDM, DS $\leq$ 26 MHz; Others $\leq$ 26 MHz
- Spread Bandwidth: $\geq$ 500 kHz (FH,DS), Spread factor $>$ 5.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous frequency-hopping mode” by spread spectrum.

Spectrum Analyzer Conditions

- RBW: 300 kHz
- VBW: 300 kHz
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Log scal: 10dB/Div
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak, Sweep mode: Continuous

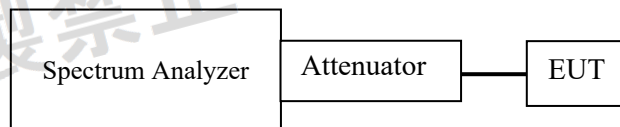
Transmitter Spurious Emission Strength and Unwanted Emission Intensity

Limit

- $f < 2387 \text{ MHz}$, $f > 2496.5 \text{ MHz}$: $\leq 2.5 \mu\text{W/MHz}$
- $2387 \text{ MHz} \leq f \leq 2400 \text{ MHz}$; $2483.5 \text{ MHz} < f \leq 2496.5 \text{ MHz}$: $\leq 25 \mu\text{W/MHz}$

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the measured value is under the technical standard value, do not need to measure more detail.

Note: $2.5 \mu\text{W/MHz} = 0.25 \mu\text{W}/100\text{kHz}$

Antenna Output Power and Antenna Power Tolerance

Limit

- $\leq 3 \text{ mW /MHz}$ (FHSS from 2402-2480 MHz)
- $\leq 10 \text{ mW/MHz}$ (OFDM, DSSS from 2400-2483.5 MHz)
- $\leq 10 \text{ mW}$ (other from 2400-2483.5 MHz)
- $\text{EIRP} \leq 6.91 \text{ dBm/MHz}$

The Output Power Tolerance must be within +20%, -80%.

Test Procedure

For FHSS UUT:

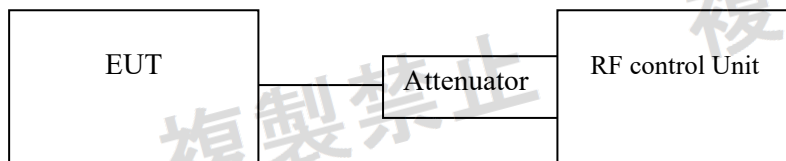
Step 1: Measure the total power by Power Meter in a state of hopping mode

Step 2: Set the power meter to trace average across the pulse on period, record the reading level on power meter.

Step 3: Calculate the mean power per 1MHz by dividing the reading level by spread bandwidth.

Output Power Density (mW/MHz) = Reading (mW) / Spread Bandwidth (MHz)

Test Setup Block diagram



Note: the power meter was integrated in the RF control Unit.

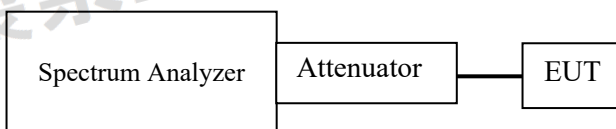
Receiver Spurious Emission and Unwanted Emission Intensity

Limit

- $\leq 4 \text{ nW}$ ($30 \text{ MHz} \leq f \leq 1000 \text{ MHz}$)
- $\leq 20 \text{ nW}$ ($1 \text{ GHz} \leq f \leq 12.5 \text{ GHz}$)

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

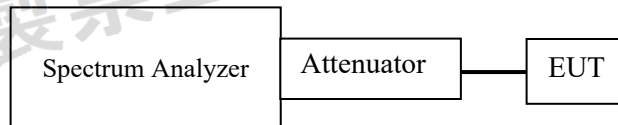
Frequency Hopping Dwell Time

Applicable Standard

According to Radio Law Radio Equipment Regulations Article 49-20, frequency dwell time is 0.4 seconds or below.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous (burst) transmission mode”. If impossible, it shall be “continuous frequency-hopping mode”.

Spectrum Analyzer Conditions

- Step 1:
 - Center Frequency: 2441.0 MHz
 - Span: ZERO SPAN
 - RBW: 1MHz, VBW: 3MHz
 - Log scale: 10dB/Div, Data points: 601points (400 points or more)
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
 - Duty cycle= Ton/(Ton+Toff)
- Step 2:
 - Center Frequency: 2441.0 MHz
 - RBW: 1MHz, VBW: 1MHz
 - Span: ZERO SPAN
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
 - Sweep time: $0.4 \times \text{SBW}[\text{second}]$

Dwell time = Time per one hopping (On time) * hopping numbers

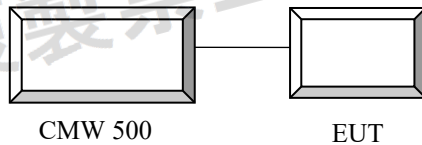
Interference Prevention Function

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

Measurement System Diagram



In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with the demodulator.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

TEST DATA AND RESULTS**Test Information:**

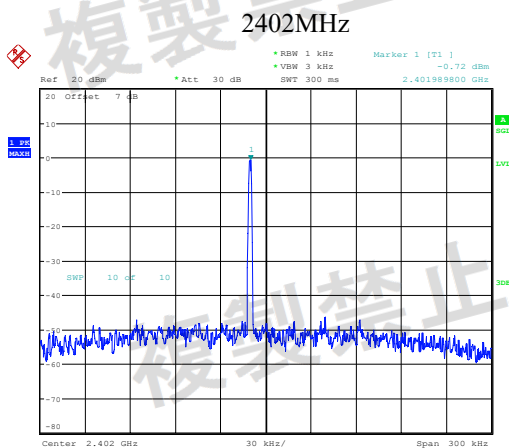
Sample No.:	3AOC-3	Test Date:	2025/10/9~2025/12/23
Test Site:	RF	Test Mode:	Transmitting
Tester:	Lee Li&Ethan Bu	Test Result:	Pass

Environmental Conditions:

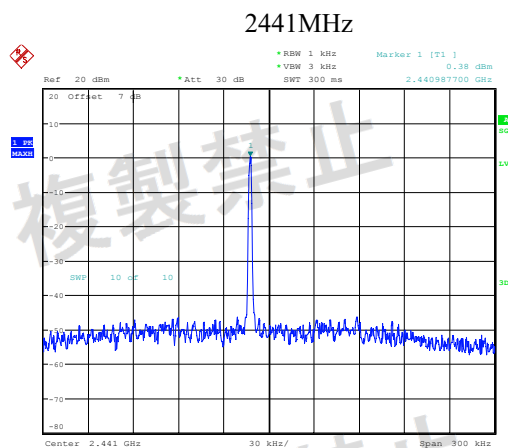
Temperature: (°C)	23.2-23.4	Relative Humidity: (%)	50-51	ATM Pressure: (kPa)	101-101.7
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Frequency Error**Test Condition: NV**

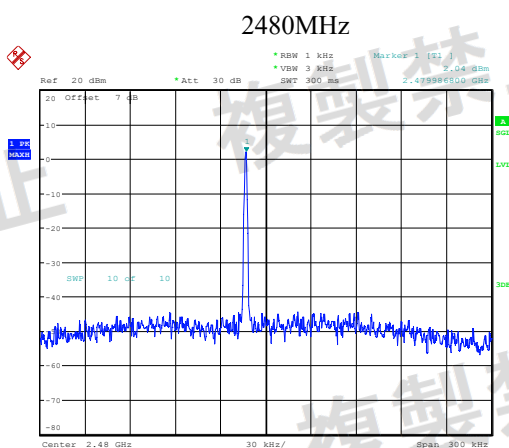
Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.98980	-4.25	± 50	Pass
	2441	2440.98770	-5.04		Pass
	2480	2479.98680	-5.32		Pass

$$\text{Frequency Tolerance} = (\text{Measure Frequency} - \text{Frequency}) / \text{Frequency} * 10^6$$
Test Condition: NV

ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 06:34:08



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 06:34:49



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 06:35:16

Occupied Bandwidth and Spreading Bandwidth**Test Condition: NV**

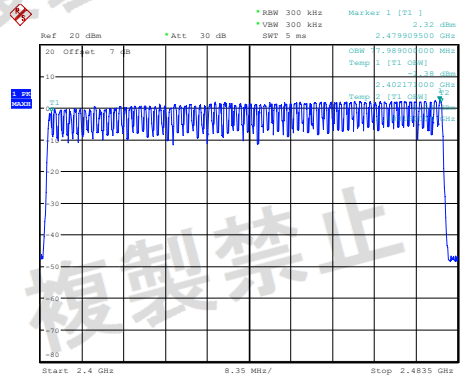
Mode	Packet Type	Occupied bandwidth (MHz)		Spreading bandwidth (MHz)		Spreading factor		Result
		Measured	Limit	Measured	Limit	Measured	Limit	
GFSK	DH1	77.989	≤ 83.5	69.723	≥ 0.5	69.723	> 5	Pass
	DH3	78.073	≤ 83.5	69.806	≥ 0.5	69.806	> 5	Pass
	DH5	78.073	≤ 83.5	69.723	≥ 0.5	69.723	> 5	Pass
$\pi/4$ -DQPSK	2DH1	78.240	≤ 83.5	69.890	≥ 0.5	69.890	> 5	Pass
	2DH3	78.240	≤ 83.5	70.808	≥ 0.5	70.808	> 5	Pass
	2DH5	78.407	≤ 83.5	69.723	≥ 0.5	69.723	> 5	Pass
8DPSK	3DH1	78.240	≤ 83.5	70.808	≥ 0.5	70.808	> 5	Pass
	3DH3	78.323	≤ 83.5	70.725	≥ 0.5	70.725	> 5	Pass
	3DH5	78.49	≤ 83.5	69.389	≥ 0.5	69.389	> 5	Pass

Note: Spread Factor = Spread Bandwidth/modulation rate. The modulation rate: MR=1.

Test Condition: NV

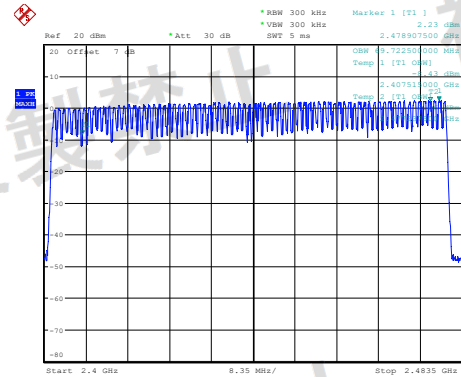
GFSK_Hopping_DH1

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:33:02

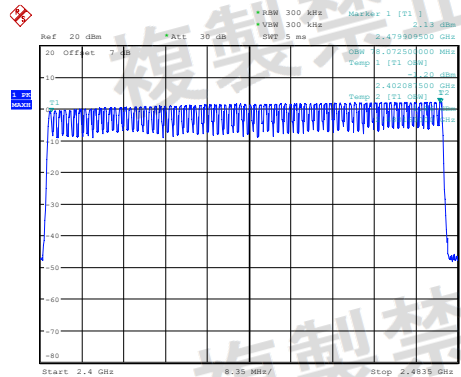
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:33:52

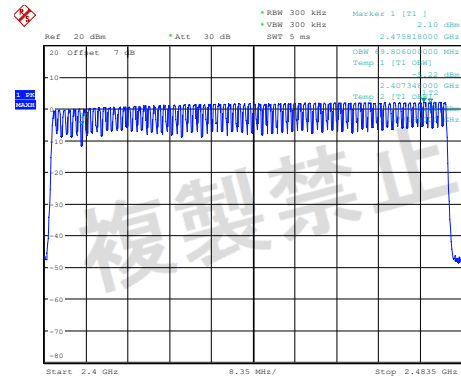
GFSK_Hopping_DH3

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:35:51

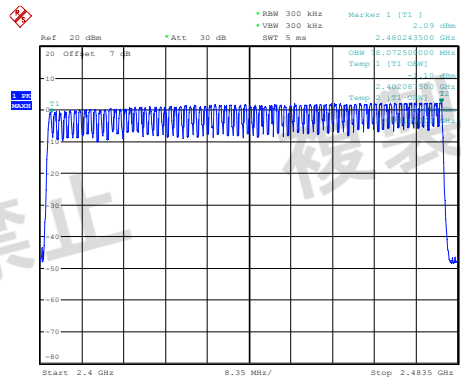
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:36:34

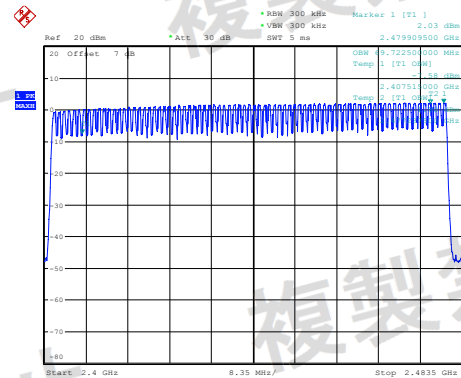
GFSK_Hopping_DH5

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:37:44

Spreading Bandwidth

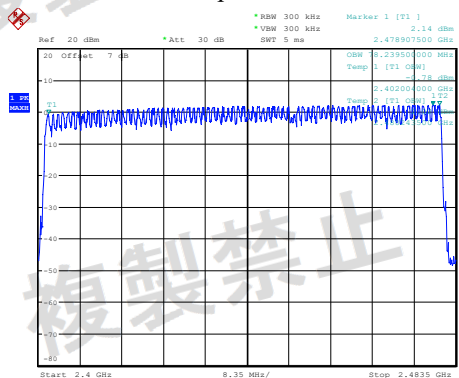


ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:38:39

Test Condition: NV

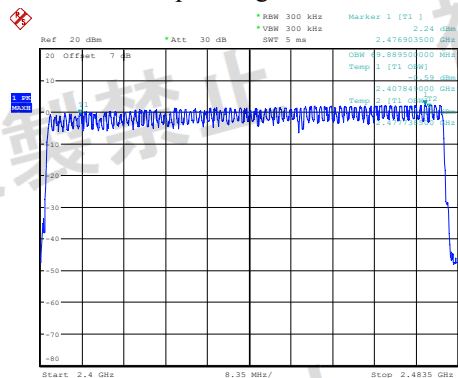
 $\pi/4$ -DQPSK_Hopping_2DH1

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:40:18

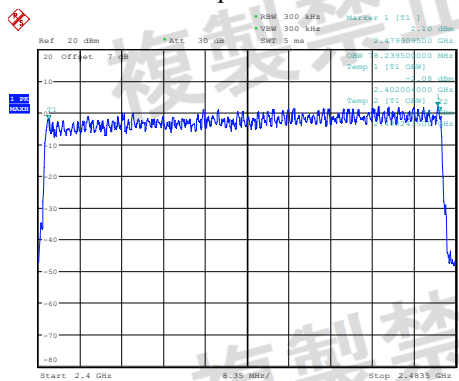
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:41:50

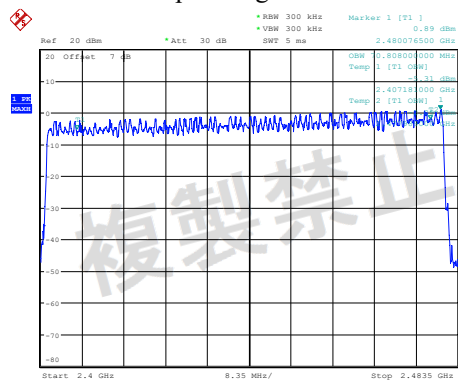
 $\pi/4$ -DQPSK_Hopping_2DH3

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:43:08

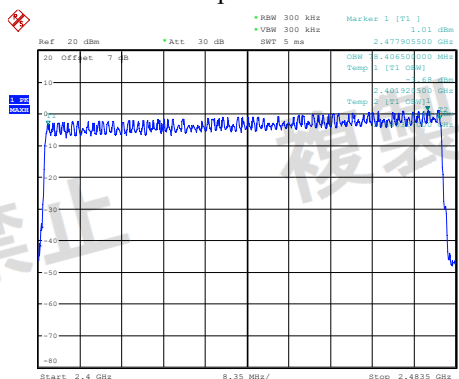
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:43:50

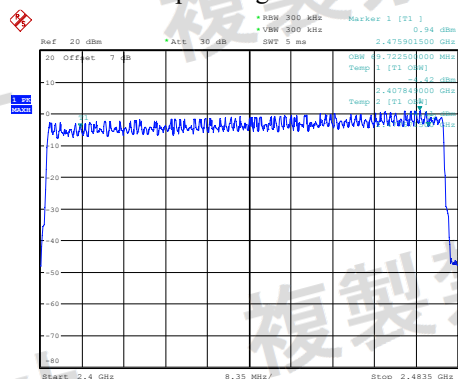
 $\pi/4$ -DQPSK_Hopping_2DH5

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:45:29

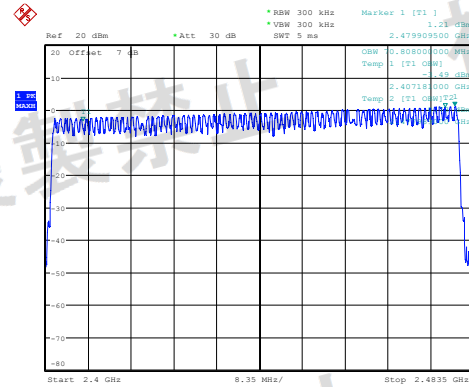
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:46:26

8DPSK_Hopping_3DH1

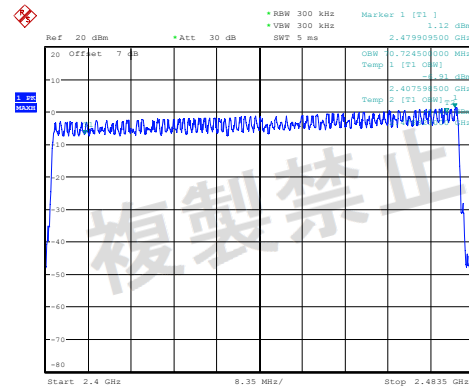
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:49:30

Occupied Bandwidth

Spreading Bandwidth

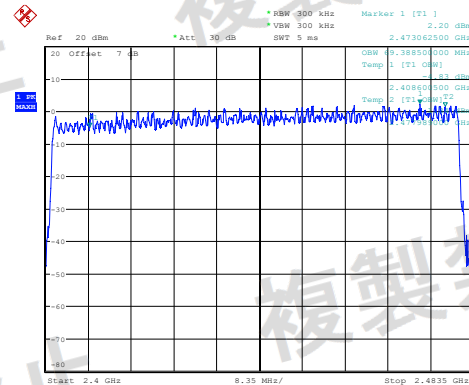


ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:52:16

Spreading Bandwidth

Occupied Bandwidth

Spreading Bandwidth



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 9.OCT.2025 07:54:22

Transmitter Spurious Emission and Unwanted Emission Intensity**Test Condition: NV, GFSK**

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	769.625	-46.58	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2348.164	-41.20	0.076	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-25.92	2.559	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2491.261	-41.33	0.074	25	Pass
	Band V (1MHz)	2496.5	12500	3501.85175	-40.14	0.097	2.50	Pass
Middle	Band I (100kHz)	30	1000	171.62	-46.11	0.024	0.25	Pass
	Band II (1MHz)	1000	2387	1676.856	-42.15	0.061	2.50	Pass
	Band III (1MHz)	2387	2400	2389.1905	-41.36	0.073	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.8205	-41.15	0.077	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-39.96	0.101	2.50	Pass
High	Band I (100kHz)	30	1000	343.31	-46.93	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2313.489	-41.99	0.063	2.50	Pass
	Band III (1MHz)	2387	2400	2396.6135	-40.67	0.086	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.6635	-40.86	0.082	25	Pass
	Band V (1MHz)	2496.5	12500	9919.097	-39.01	0.126	2.50	Pass

Test Condition: NV, π/4-DQPSK

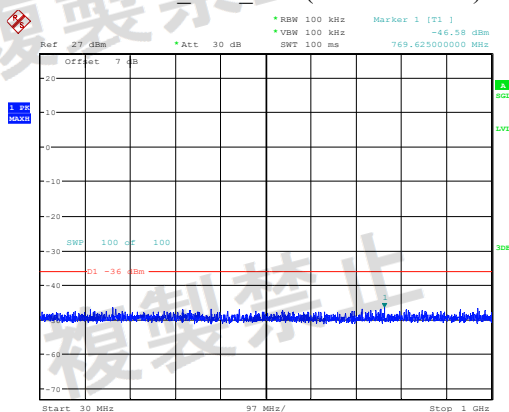
Channel	Test Band (RBW)	Start (MHz)	Stop (MHz)	Max.Emission Located(MHz)	Result (dBm/RBW)	Result (nW/RBW)	Limit (nW/RBW)	Verdict
Low	Band I (100kHz)	30	1000	811.82	-46.45	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2241.365	-41.79	0.066	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-23.09	4.909	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.856	-40.48	0.090	25	Pass
	Band V (1MHz)	2496.5	12500	3491.84825	-40.09	0.098	2.50	Pass
Middle	Band I (100kHz)	30	1000	160.95	-47.08	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2173.402	-41.82	0.066	2.50	Pass
	Band III (1MHz)	2387	2400	2387.026	-41.32	0.074	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.809	-40.08	0.098	25	Pass
	Band V (1MHz)	2496.5	12500	3511.85525	-39.35	0.116	2.50	Pass
High	Band I (100kHz)	30	1000	510.635	-46.69	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2332.907	-41.14	0.077	2.50	Pass
	Band III (1MHz)	2387	2400	2397.699	-41.41	0.072	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.617	-38.19	0.152	25	Pass
	Band V (1MHz)	2496.5	12500	9924.09875	-37.53	0.177	2.50	Pass

Test Condition: NV, 8DPSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	870.99	-46.61	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2269.7985	-41.97	0.064	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-23.12	4.875	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2491.7615	-40.13	0.097	25	Pass
	Band V (1MHz)	2496.5	12500	3496.85	-39.72	0.107	2.50	Pass
Middle	Band I (100kHz)	30	1000	304.025	-46.85	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2211.5445	-42.24	0.060	2.50	Pass
	Band III (1MHz)	2387	2400	2387.728	-40.94	0.081	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.1395	-41.20	0.076	25	Pass
	Band V (1MHz)	2496.5	12500	3486.8465	-39.61	0.109	2.50	Pass
High	Band I (100kHz)	30	1000	598.905	-46.53	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2181.724	-41.89	0.065	2.50	Pass
	Band III (1MHz)	2387	2400	2390.432	-41.52	0.070	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5065	-36.72	0.213	25	Pass
	Band V (1MHz)	2496.5	12500	9919.097	-39.39	0.115	2.50	Pass

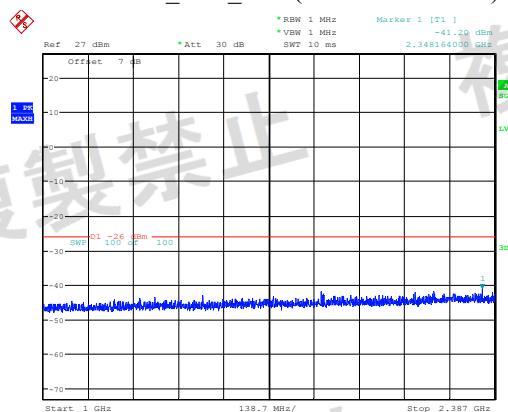
Test Condition: NV

GFSK_Low_DH1(30MHz~1GHz)



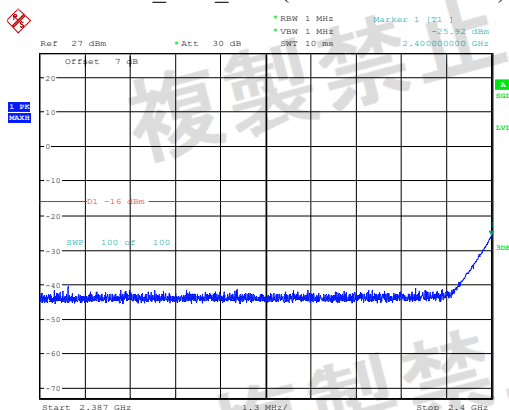
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:22:25

GFSK_Low_DH1(1GHz~2.387GHz)



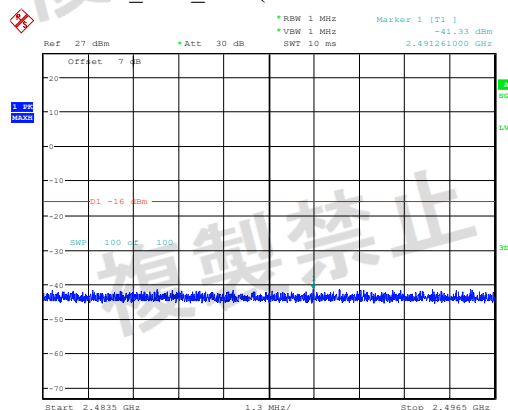
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:22:39

GFSK_Low_DH1(2.387GHz~2.4GHz)



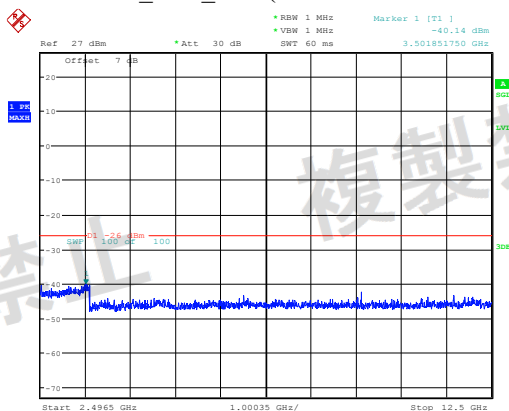
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:22:52

GFSK_Low_DH1(2.4835GHz~2.4965GHz)



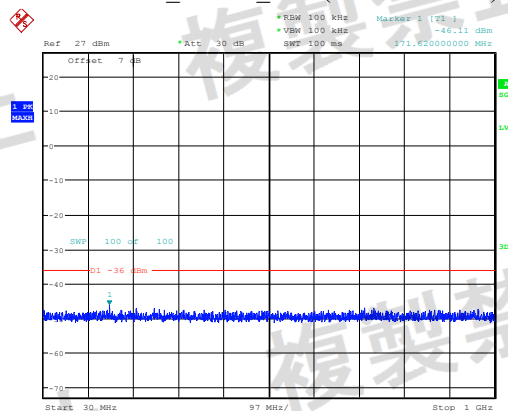
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Date: 10.OCT.2025 01:23:04

GFSK_Low_DH1(2.4965GHz~12.5GHz)



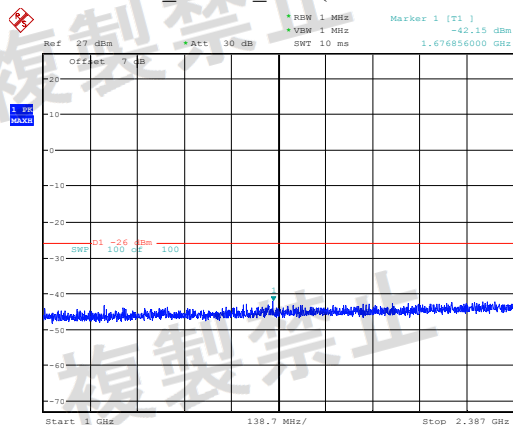
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Date: 10.OCT.2025 01:23:34

GFSK_Middle_DH1(30MHz~1GHz)



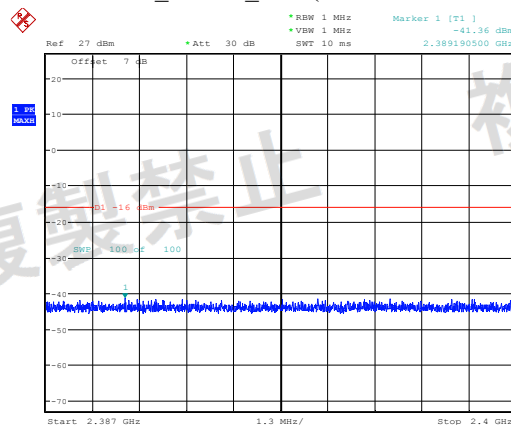
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:25:02

GFSK_Middle_DH1(1GHz~2.387GHz)



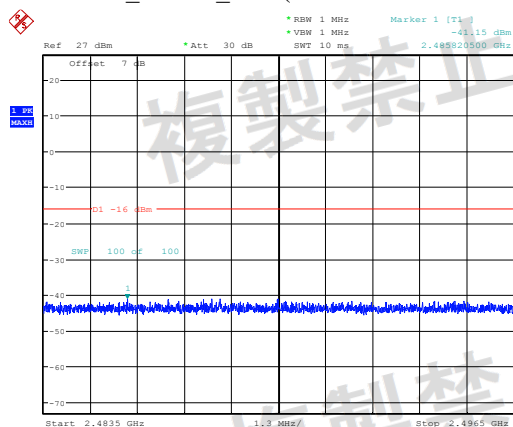
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:25:15

GFSK_Middle_DH1(2.387GHz~2.4GHz)



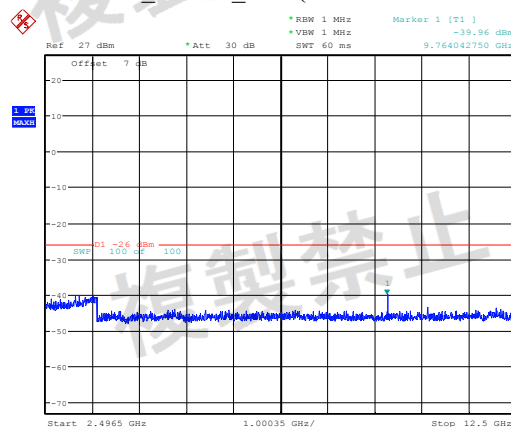
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:25:28

GFSK_Middle_DH1(2.4835GHz~2.4965GHz)



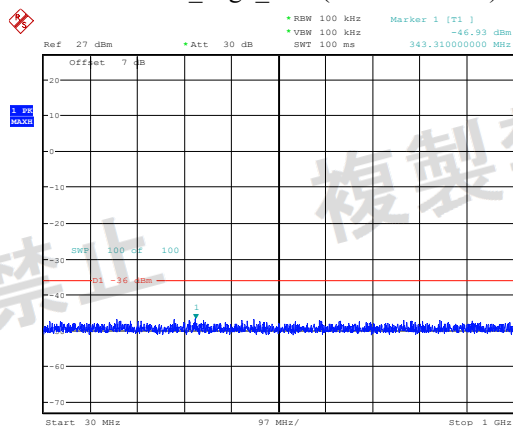
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:25:40

GFSK_Middle_DH1(2.4965GHz~12.5GHz)



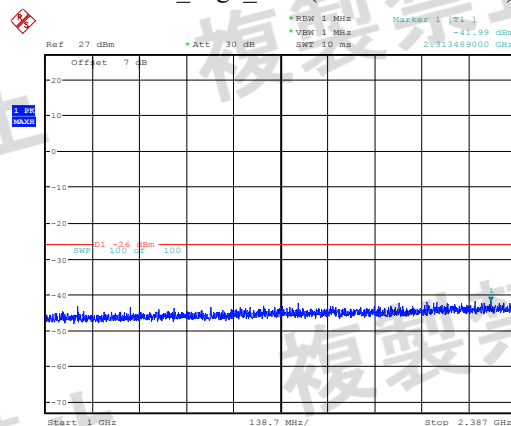
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:26:09

GFSK_High_DH1(30MHz~1GHz)



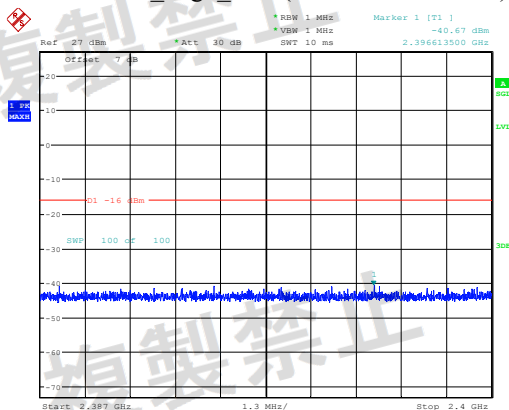
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:27:00

GFSK_High_DH1(1GHz~2.387GHz)



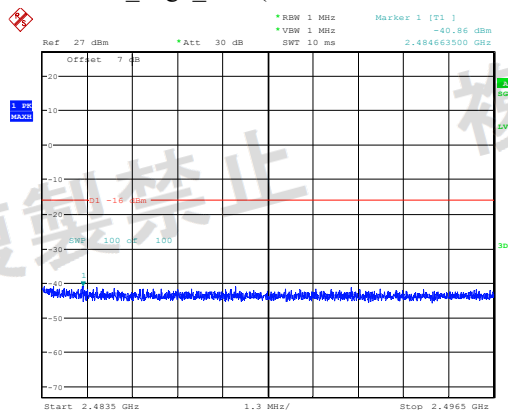
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:27:14

GFSK_High_DH1(2.387GHz~2.4GHz)



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:27:27

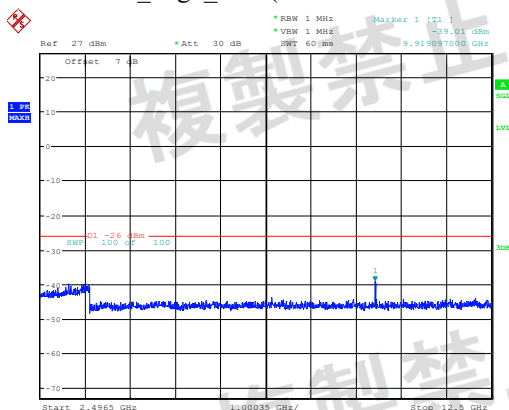
GFSK_High_DH1(2.4835GHz~2.4965GHz)



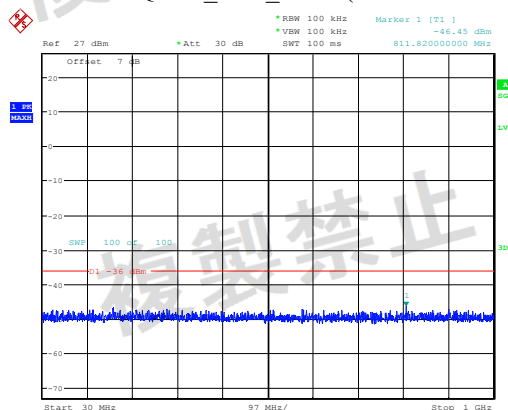
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 03:27:40

Test Condition: NV

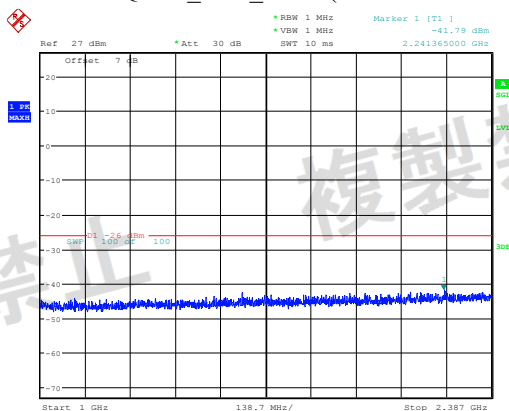
GFSK_High_DH1(2.4965GHz~12.5GHz)



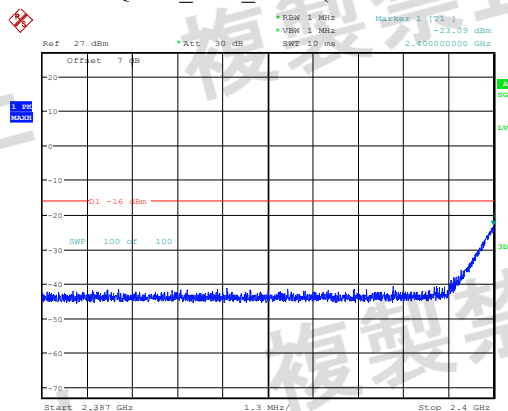
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:28:09

 $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

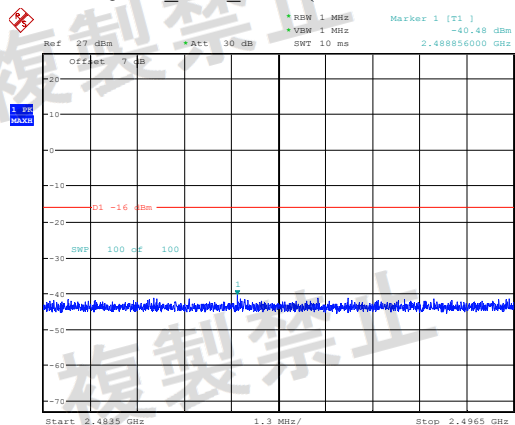
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:29:38

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~2.387GHz)

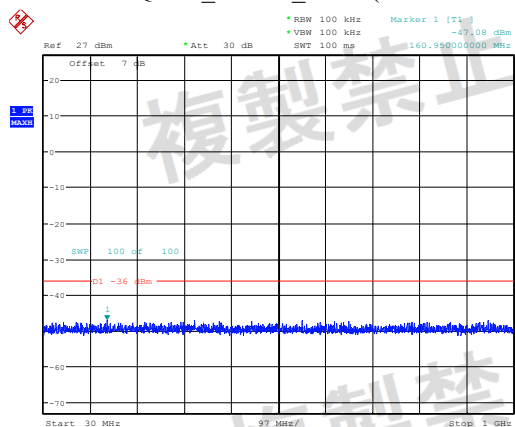
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:29:53

 $\pi/4$ -DQPSK_Low_2DH1(2.387GHz~2.4GHz)

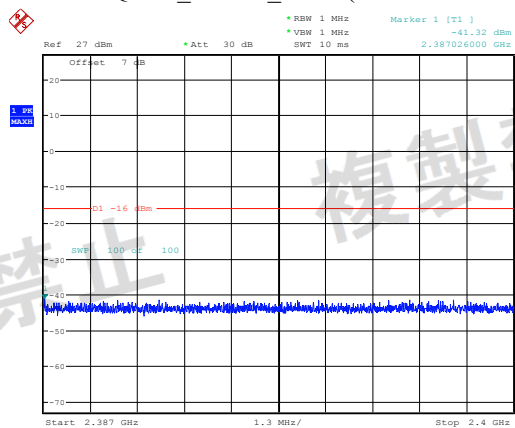
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:30:06

$\pi/4$ -DQPSK_Low_2DH1(2.4835GHz~2.4965GHz)

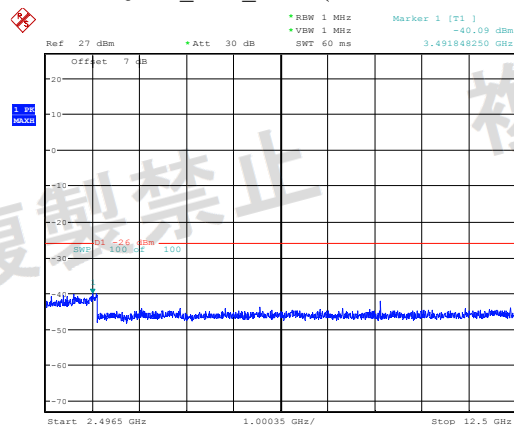
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:30:18

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

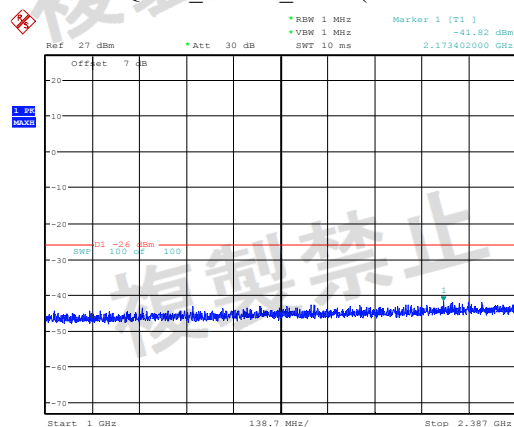
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:31:54

 $\pi/4$ -DQPSK_Middle_2DH1(2.387GHz~2.4GHz)

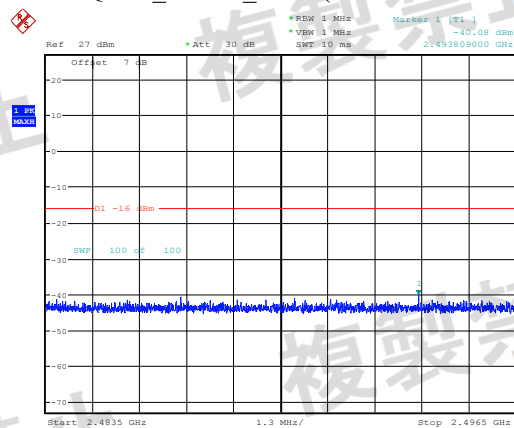
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:32:20

 $\pi/4$ -DQPSK_Low_2DH1(2.4965GHz~12.5GHz)

ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:30:48

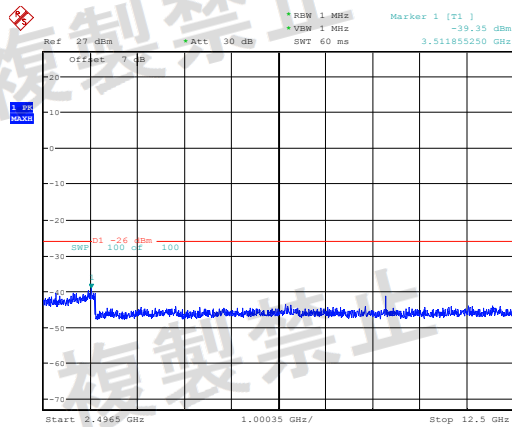
 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~2.387GHz)

ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:32:08

 $\pi/4$ -DQPSK_Middle_2DH1(2.4835GHz~2.4965GHz)

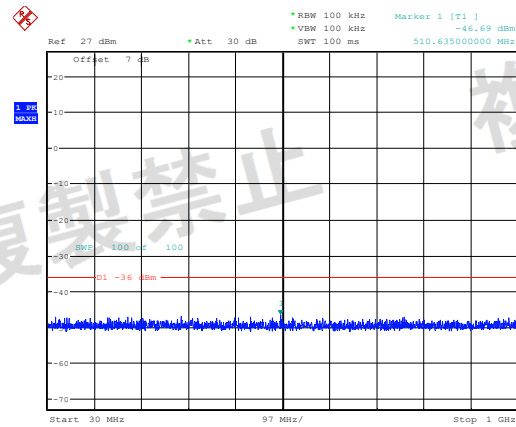
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:32:33

$\pi/4$ -DQPSK_Middle_2DH1(2.4965GHz~12.5GHz)



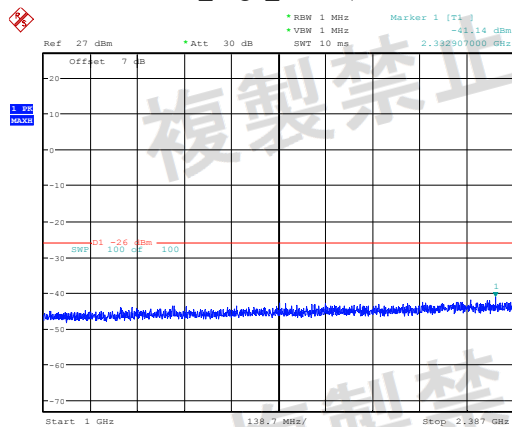
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:33:03

$\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)



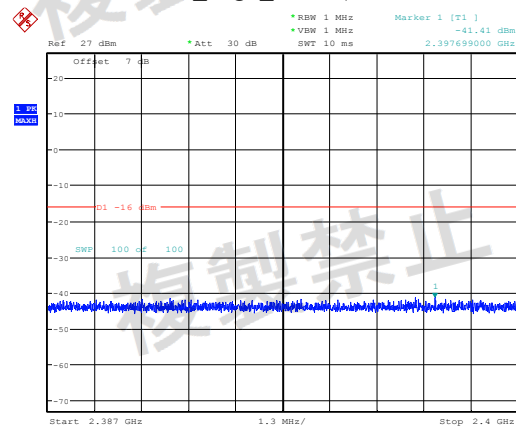
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Date: 10.OCT.2025 01:33:37

$\pi/4$ -DQPSK_High_2DH1(1GHz~2.387GHz)



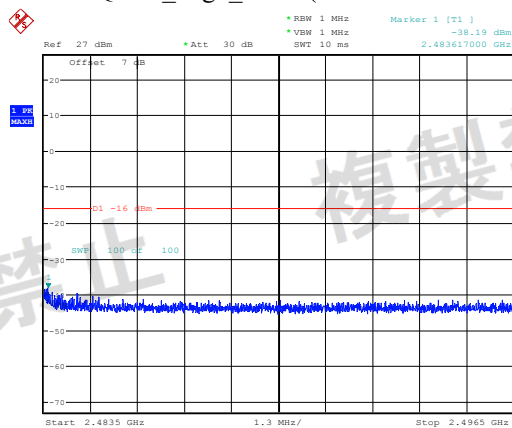
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:33:51

$\pi/4$ -DQPSK_High_2DH1(2.387GHz~2.4GHz)



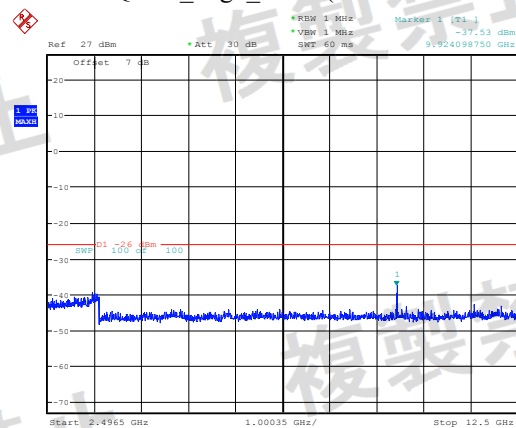
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:34:03

$\pi/4$ -DQPSK_High_2DH1(2.4835GHz~2.4965GHz)



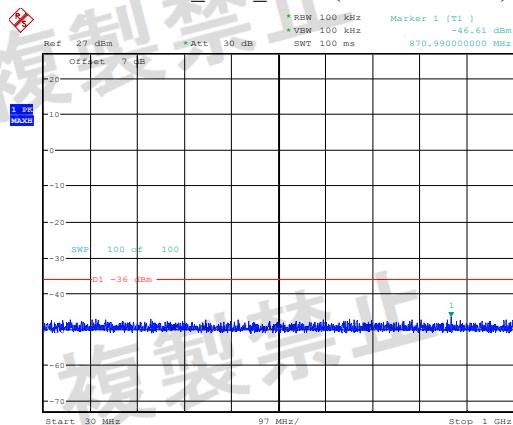
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:34:15

$\pi/4$ -DQPSK_High_2DH1(2.4965GHz~12.5GHz)



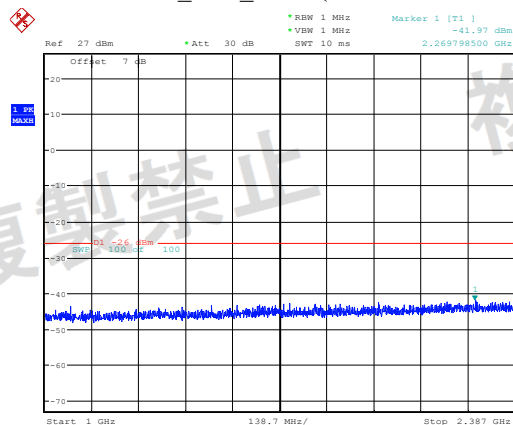
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:34:45

8DPSK_Low_3DH1(30MHz~1GHz)



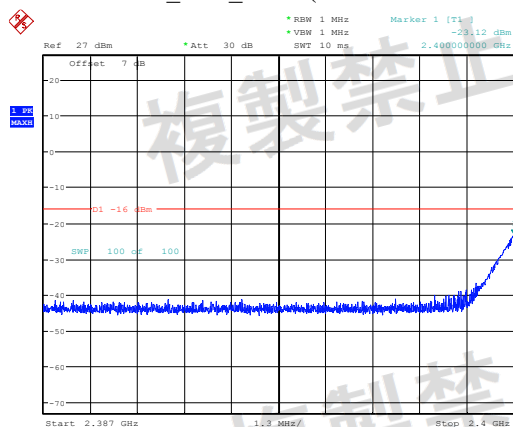
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:36:15

8DPSK_Low_3DH1(1GHz~2.387GHz)



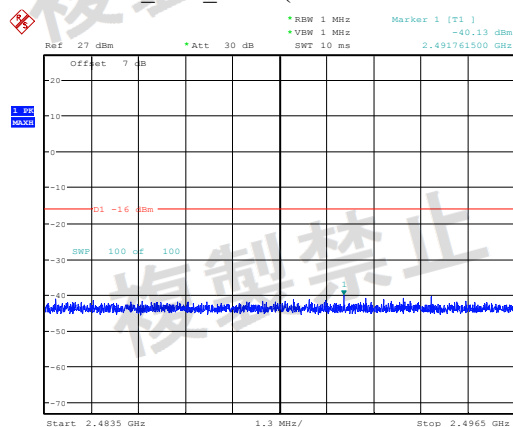
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:36:29

8DPSK_Low_3DH1(2.387GHz~2.4GHz)



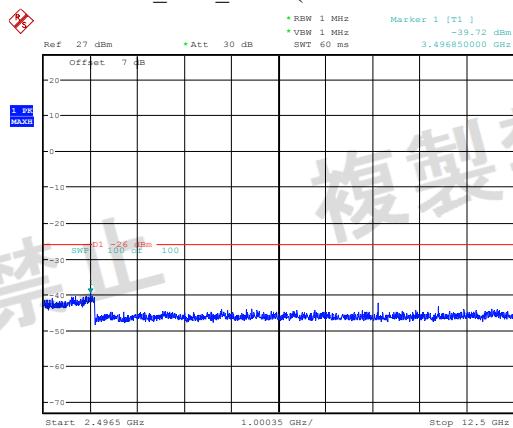
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:36:41

8DPSK_Low_3DH1(2.4835GHz~2.4965GHz)



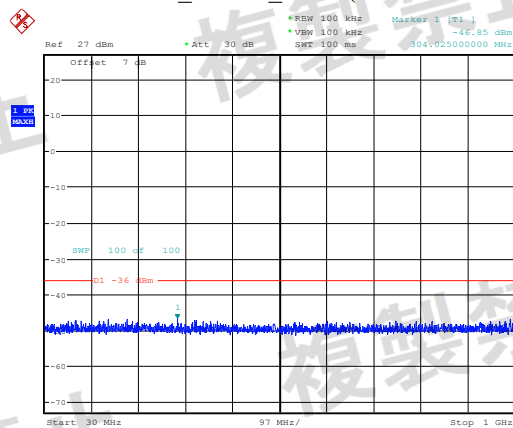
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:36:54

8DPSK_Low_3DH1(2.4965GHz~12.5GHz)



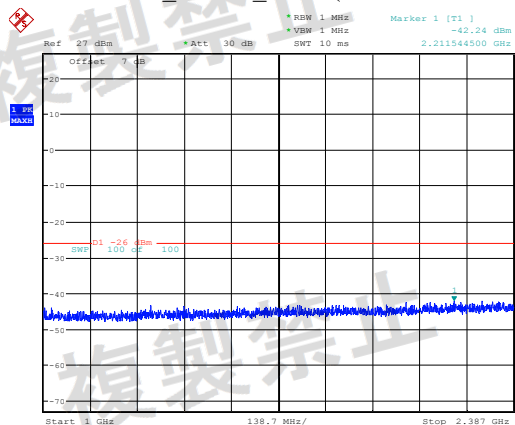
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:37:23

8DPSK_Middle_3DH1(30MHz~1GHz)



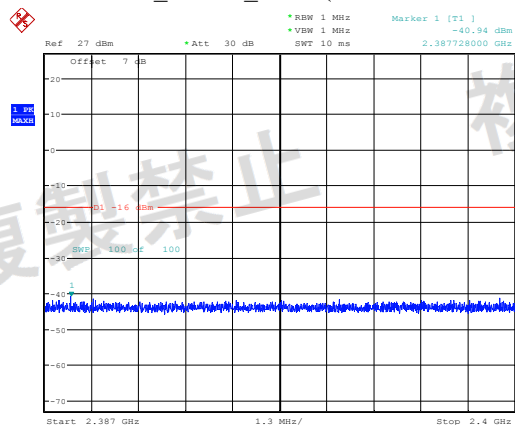
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:38:08

8DPSK_Middle_3DH1(1GHz~2.387GHz)



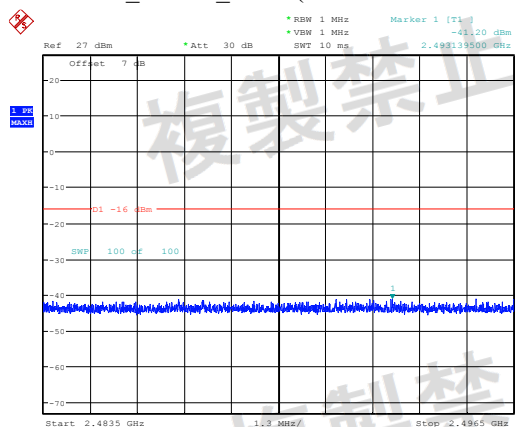
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:38:22

8DPSK_Middle_3DH1(2.387GHz~2.4GHz)



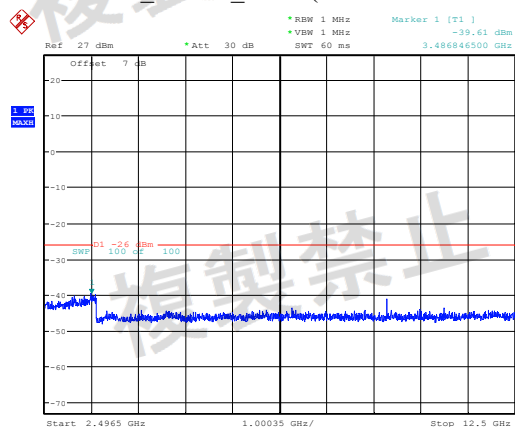
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:38:34

8DPSK_Middle_3DH1(2.4835GHz~2.4965GHz)



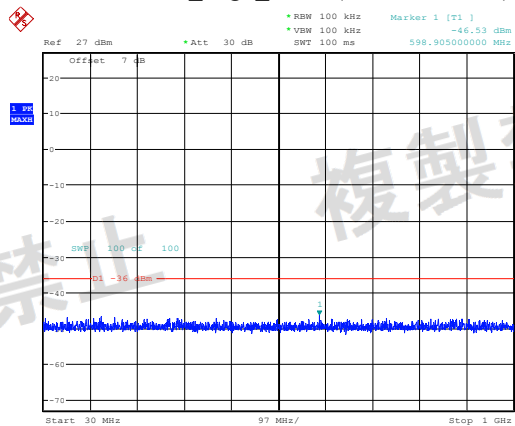
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:38:47

8DPSK_Middle_3DH1(2.4965GHz~12.5GHz)



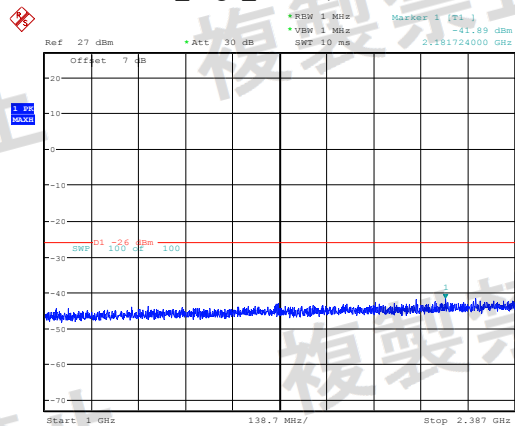
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:39:16

8DPSK_High_3DH1(30MHz~1GHz)

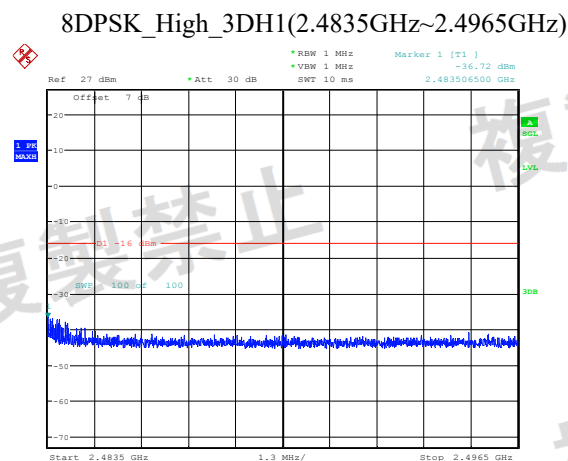


ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:39:50

8DPSK_High_3DH1(1GHz~2.387GHz)



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:40:04



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 01:40:28

Antenna Output Power and Output Power Tolerance**Test Condition: NV**

Mode	Antenna gain (dBi)	Declared power (mW/MHz)
GFSK	1.70	0.02
$\pi/4$ DQPSK		0.02
8DPSK		0.02

Test Condition: NV

Mode	Antenna output power (dBm)	Spread bandwidth (MHz)	Antenna output power (mW/MHz)		Antenna output power tolerance(%)		EIRP (dBm/MHz)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
GFSK	0.37	69.723	0.016	≤ 3	-21.91	-80~+20	-16.364	≤ 6.91	Pass
$\pi/4$ -DQPSK	-1.77	69.890	0.010	≤ 3	-52.41	-80~+20	-18.514	≤ 6.91	Pass
8DPSK	-1.82	70.808	0.009	≤ 3	-53.56	-80~+20	-18.621	≤ 6.91	Pass

Note:

Antenna output power(mW) = $10^{\{\text{Antenna output power(dBm)} / 10\}}$

Antenna output power(mW/MHz) = Antenna output power(mW) / Spread bandwidth(MHz)

Antenna output power Tolerance(%) = (Antenna output power(mW/MHz) - Declared power) / Declared power * 100%

Antenna output power(dBm/MHz) = $10 * \log_{10}\{\text{Antenna output power(mW/MHz)}\}$

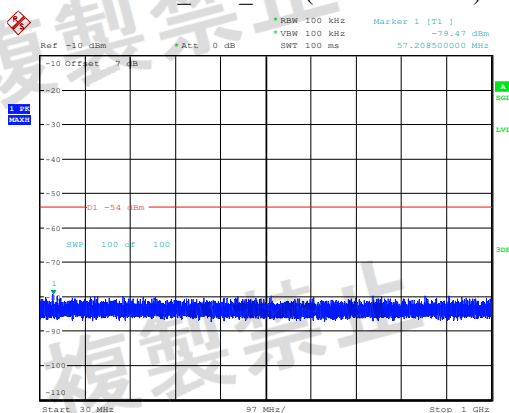
EIRP(dBm/MHz) = Antenna output power(dBm/MHz) + Antenna gain.

Receiver Spurious Emission and Unwanted Emission Intensity**Test Condition: NV**

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
GFSK	Low	Band I (100kHz)	30	1000	57.2085	-79.47	0.011	4	Pass
		Band II (1MHz)	1000	12500	3535.175	-71.13	0.077	20	Pass
	Middle	Band I (100kHz)	30	1000	674.9045	-78.76	0.013	4	Pass
		Band II (1MHz)	1000	12500	3563.925	-71.53	0.070	20	Pass
	High	Band I (100kHz)	30	1000	815.118	-79.12	0.012	4	Pass
		Band II (1MHz)	1000	12500	3422.475	-71.65	0.068	20	Pass
$\pi/4$ -DQPSK	Low	Band I (100kHz)	30	1000	178.7495	-79.27	0.012	4	Pass
		Band II (1MHz)	1000	12500	3521.375	-70.67	0.086	20	Pass
	Middle	Band I (100kHz)	30	1000	319.7875	-79.06	0.012	4	Pass
		Band II (1MHz)	1000	12500	3545.525	-71.81	0.066	20	Pass
	High	Band I (100kHz)	30	1000	906.3465	-79.46	0.011	4	Pass
		Band II (1MHz)	1000	12500	3534.6	-71.70	0.068	20	Pass
8DPSK	Low	Band I (100kHz)	30	1000	737.5665	-78.88	0.013	4	Pass
		Band II (1MHz)	1000	12500	3599	-70.70	0.085	20	Pass
	Middle	Band I (100kHz)	30	1000	485.318	-79.25	0.012	4	Pass
		Band II (1MHz)	1000	12500	3516.775	-70.89	0.081	20	Pass
	High	Band I (100kHz)	30	1000	908.7715	-79.30	0.012	4	Pass
		Band II (1MHz)	1000	12500	3418.45	-71.10	0.078	20	Pass

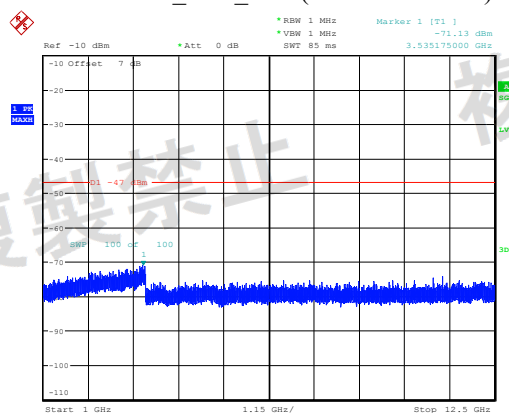
Test Condition: NV

GFSK_Low_DH1(30MHz~1GHz)



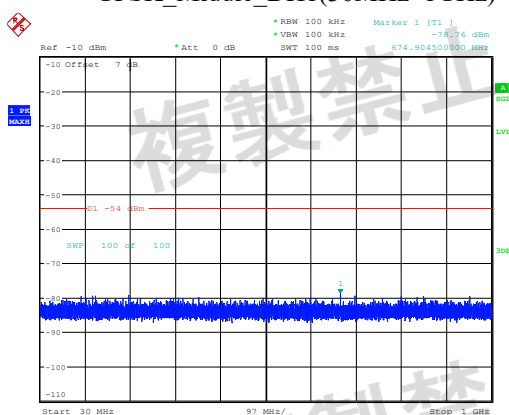
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:23:24

GFSK_Low_DH1(1GHz~12.5GHz)



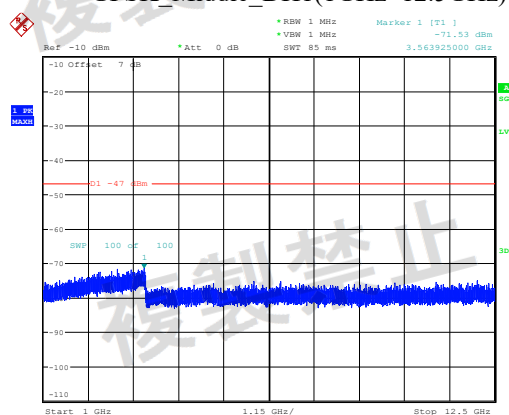
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:24:00

GFSK_Middle_DH1(30MHz~1GHz)



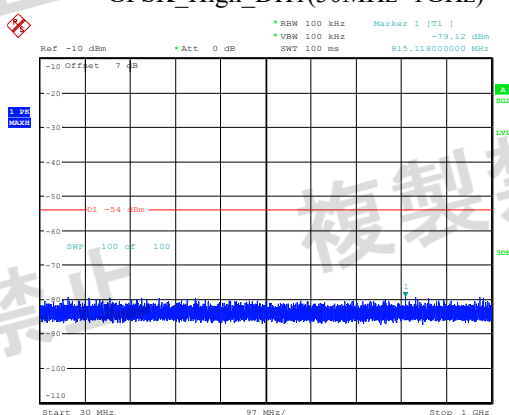
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:24:42

GFSK_Middle_DH1(1GHz~12.5GHz)



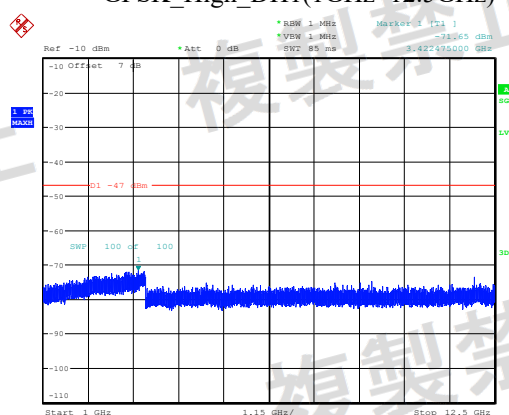
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:25:18

GFSK_High_DH1(30MHz~1GHz)



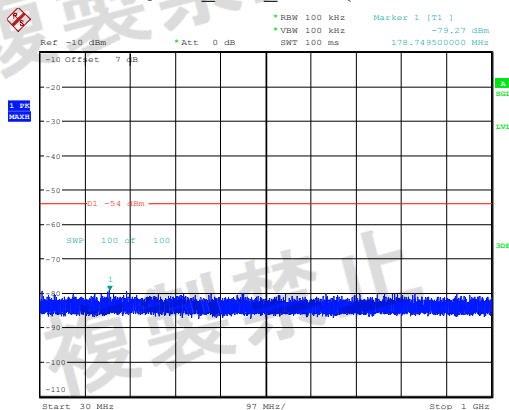
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:25:50

GFSK_High_DH1(1GHz~12.5GHz)

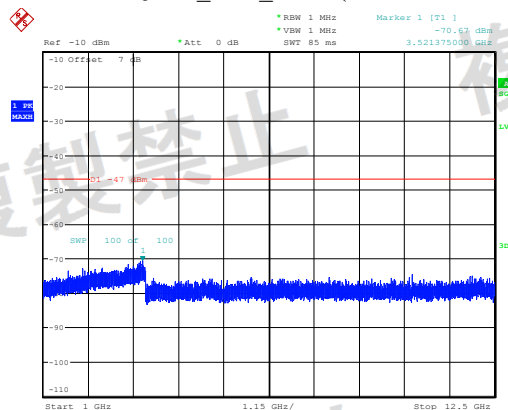


ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:26:25

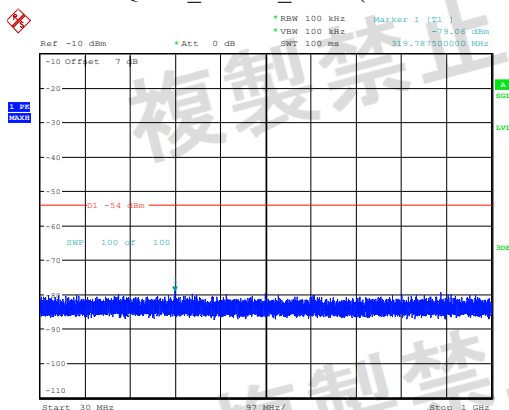
Test Condition: NV

 $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

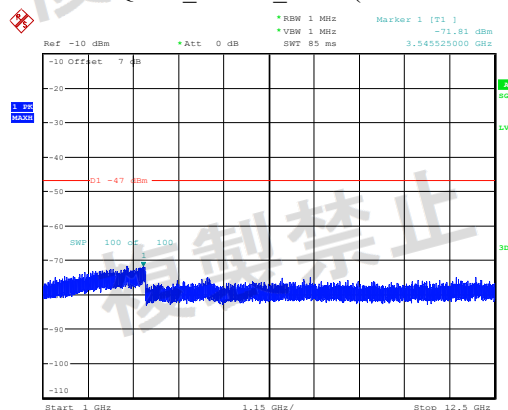
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:27:09

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~12.5GHz)

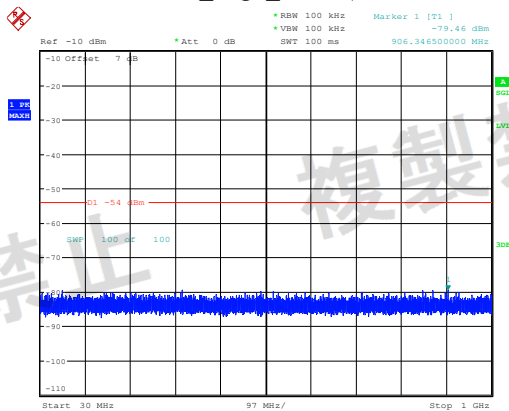
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:27:44

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

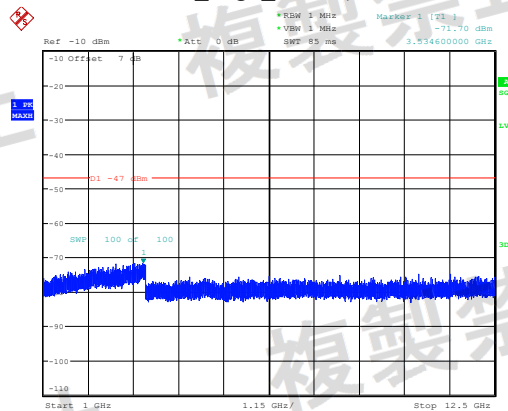
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:28:12

 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:28:48

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

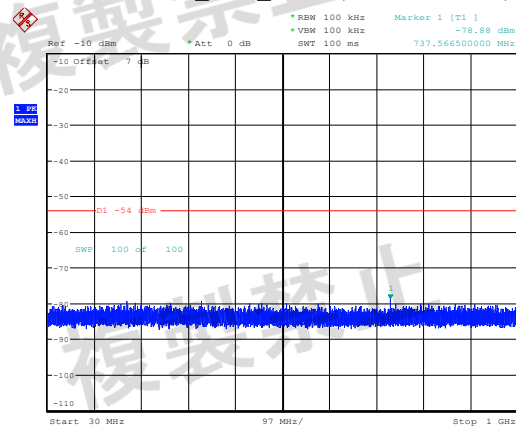
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:29:19

 $\pi/4$ -DQPSK_High_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:29:55

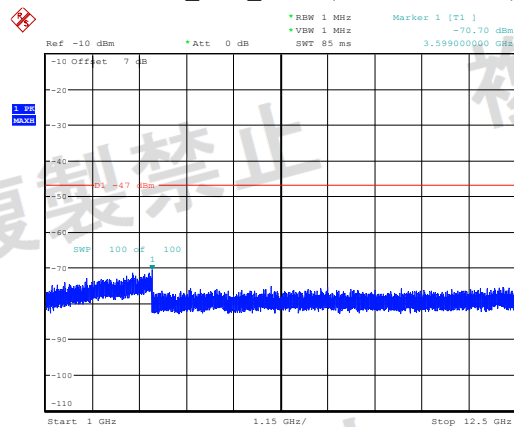
Test Condition: NV

8DPSK_Low_3DH1(30MHz~1GHz)



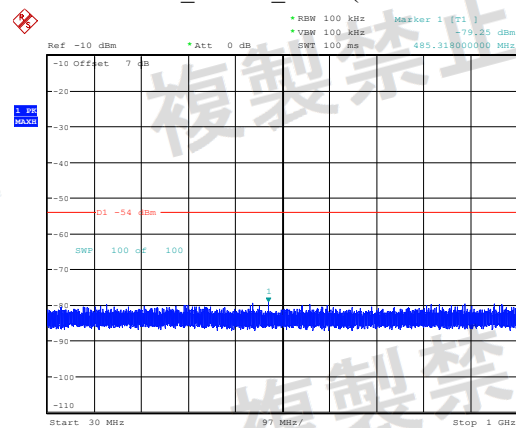
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:30:23

8DPSK_Low_3DH1(1GHz~12.5GHz)



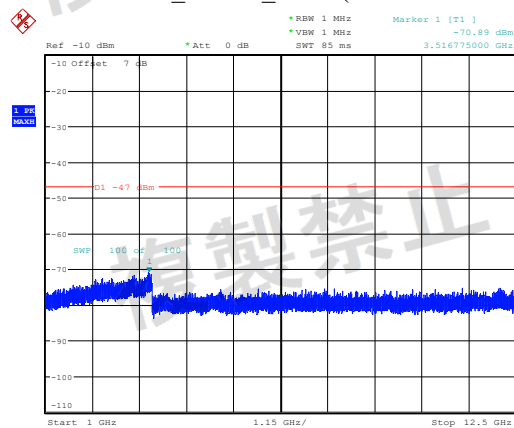
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:30:58

8DPSK_Middle_3DH1(30MHz~1GHz)



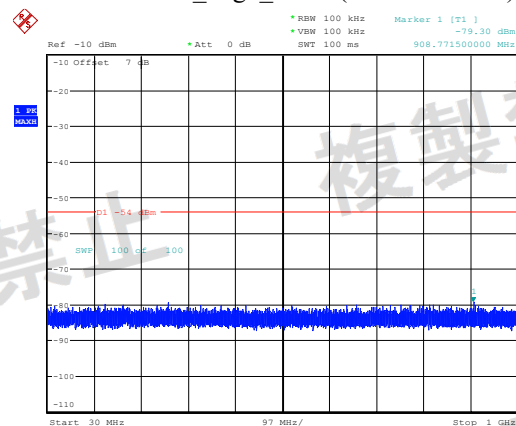
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:31:26

8DPSK_Middle_3DH1(1GHz~12.5GHz)



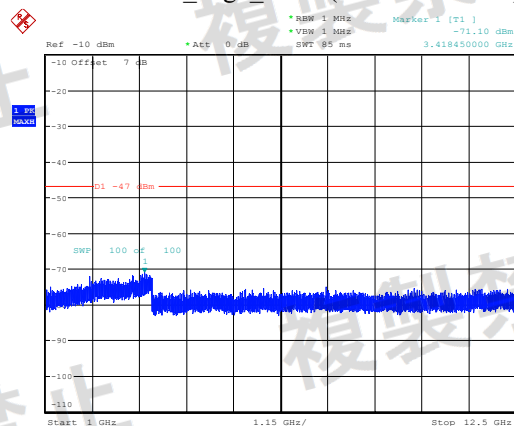
ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:32:01

8DPSK_High_3DH1(30MHz~1GHz)



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:32:52

8DPSK_High_3DH1(1GHz~12.5GHz)



ProjectNo.:2501X79555E-RF(L) Tester:Lee Li
Date: 10.OCT.2025 02:33:27

Frequency Hopping Dwell Time**Test Condition: NV**

Mode	Packet Type	Spreading bandwidth	Ton (ms)	Observed Period(s)	Hopping Number In Observed Period	Result (s)	Limit(s)	Verdict
GFSK	DH1	69.723	0.391	27.8892	206	0.081	≤ 0.4	Pass
	DH3	69.806	1.652	27.9224	119	0.197		Pass
	DH5	69.723	2.908	27.8892	82	0.238		Pass
$\pi/4$ -DQPSK	2DH1	69.890	0.402	27.9560	206	0.083		Pass
	2DH3	70.808	1.655	28.3232	121	0.200		Pass
	2DH5	69.723	2.913	27.8892	80	0.233		Pass
8DPSK	3DH1	70.808	0.396	28.3232	205	0.081		Pass
	3DH3	70.725	1.655	28.2900	127	0.210		Pass
	3DH5	69.389	2.908	27.7556	84	0.244		Pass

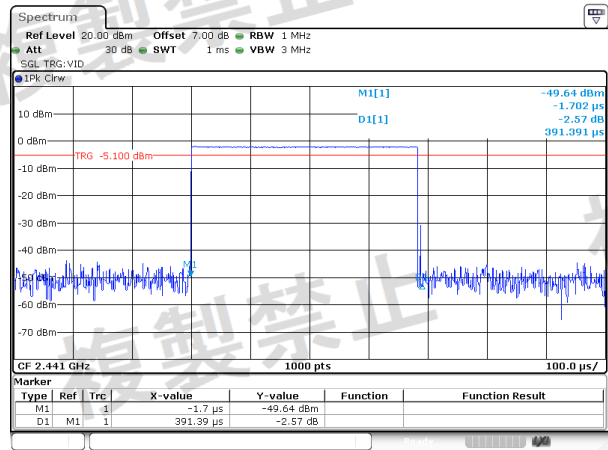
Note:

1. Dwell time = Time per one hopping (Ton) * hopping number (within the time obtained by multiplying the spread rate by 0.4s).

2. The Spread Bandwidth please refer to Occupied Bandwidth and Spreading Bandwidth.

Test Condition: NV

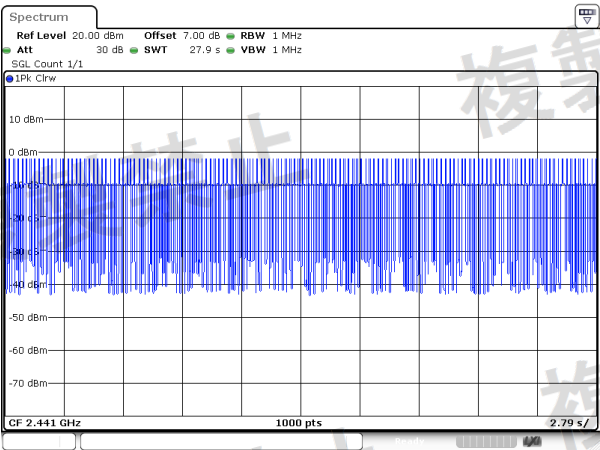
GFSK_Hopping_DH1



ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu

Date: 23.DEC.2025 18:27:09

GFSK_Hopping_DH1

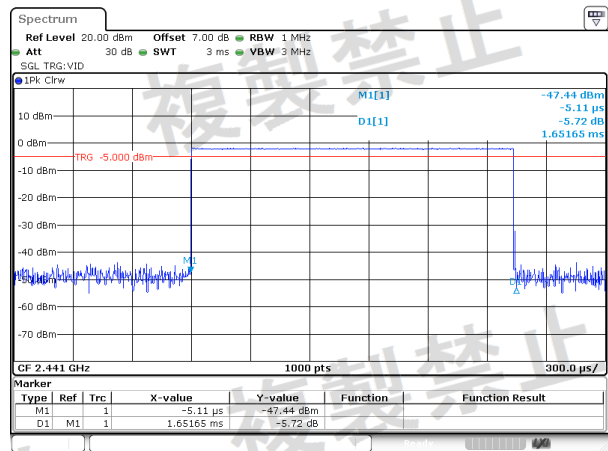


ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu

Date: 23.DEC.2025 18:40:24

Test Condition: NV

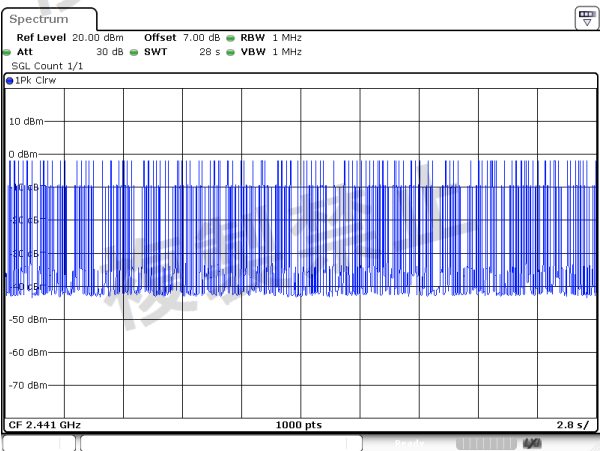
GFSK_Hopping_DH3



ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu

Date: 23.DEC.2025 17:08:09

GFSK_Hopping_DH3

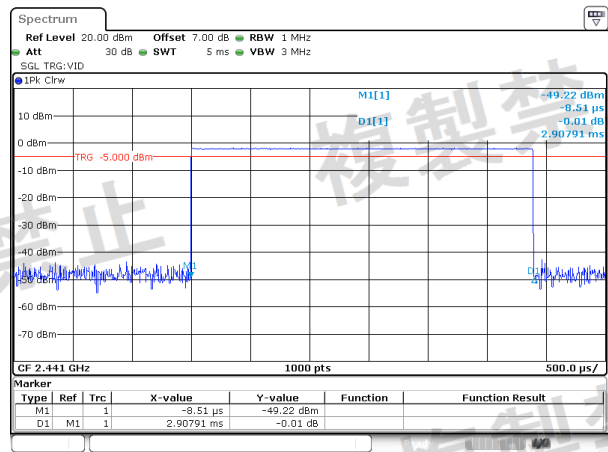


ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu

Date: 23.DEC.2025 17:14:23

Test Condition: NV

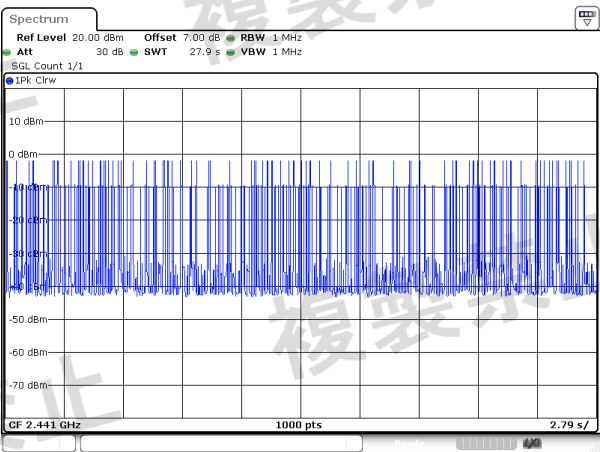
GFSK_Hopping_DH5



ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu

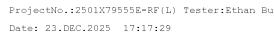
Date: 23.DEC.2025 17:15:22

GFSK_Hopping_DH5



ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu

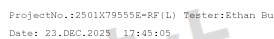
Date: 23.DEC.2025 17:16:52

$\pi/4$ -DQPSK_Hopping_2DH1

ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu
Date: 23.DEC.2025 17:18:20

 $\pi/4$ -DQPSK_Hopping_2DH3

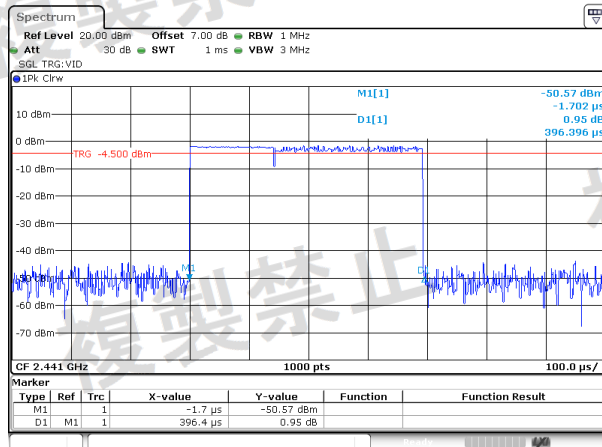
ProjectNo.:2501X79555E-RF(L) Tester:Ethan Bu
Date: 23.DEC.2025 17:44:14

 $\pi/4$ -DQPSK_Hopping_2DH5

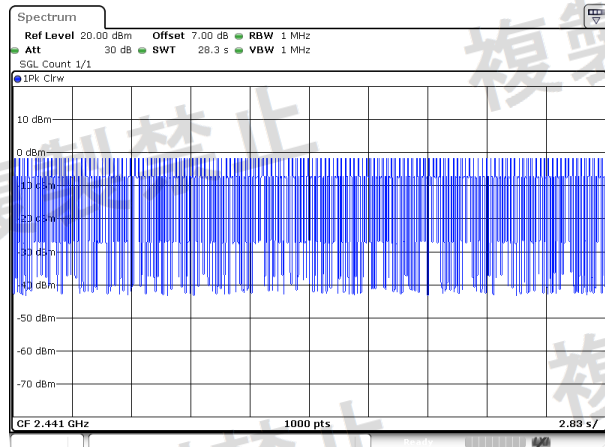
ProjectNo.:2501X79555E-RF{L} Tester:Ethan Bu
Date: 23.DEC.2025 17:46:07

Test Condition: NV

8DPSK_Hopping_3DH1

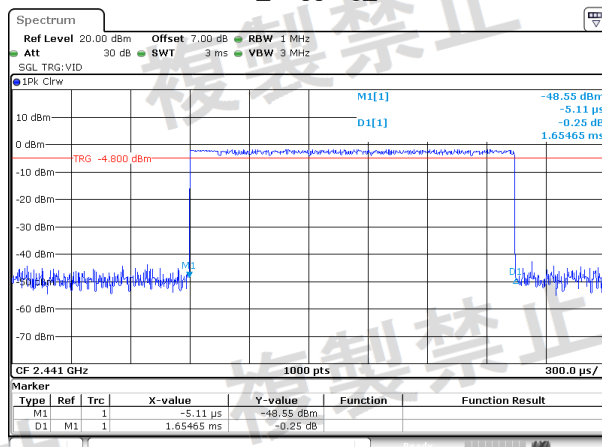


8DPSK_Hopping_3DH1

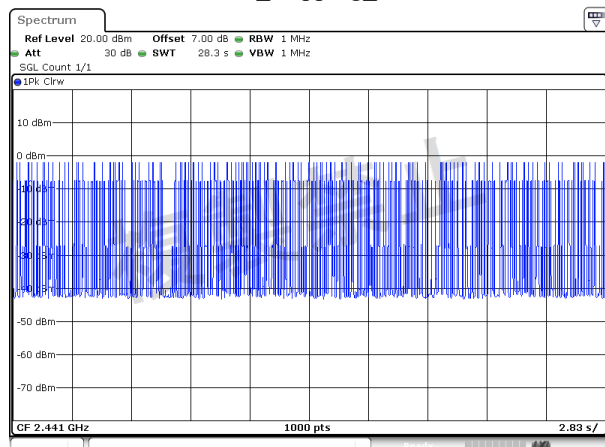


Test Condition: NV

8DPSK_Hopping_3DH3

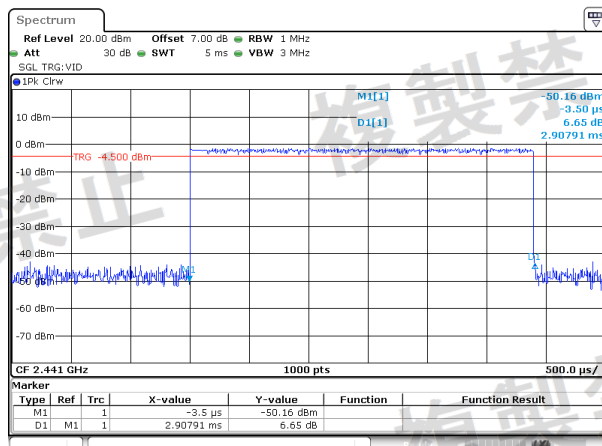


8DPSK_Hopping_3DH3

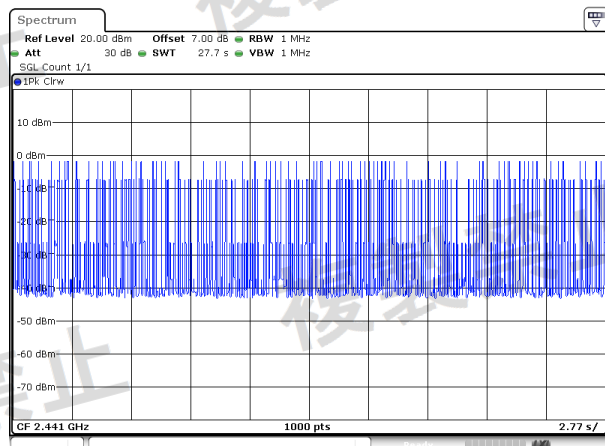


Test Condition: NV

8DPSK_Hopping_3DH5



8DPSK_Hopping_3DH5



Interference Prevention Function**Test Information:**

Sample No.:	3AOC-3	Test Date:	2025/10/10
Test Site:	RF	Test Mode:	Communicating
Tester:	Lee Li	Test Result:	Good

Environmental Conditions:

Temperature: (°C)	23.4	Relative Humidity: (%)	51	ATM Pressure: (kPa)	101.7
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CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Result

The EUT shell is glued together which can't be opened easily, please see the EUT photos.

EUT PHOTOGRAPHS

Please refer to the attachment 2501X79555E-RF-EXP External photo and 2501X79555E-RF-INP Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501X79555E-RF-07A-TSP Test Setup photo.

****END OF REPORT****